



# IV/CV for TEG/WAT – Flex T&M

Supported:  
Keysight(Agilent/HP)

- ✓ MOSFET
- ✓ TFT
- ✓ BJT
- ✓ DIODE
- ✓ RESISTENCE
- ✓ 4 POINTS Rs
- ✓ CAPACITOR
- ✓ LED
- ✓ SOLAR CELL

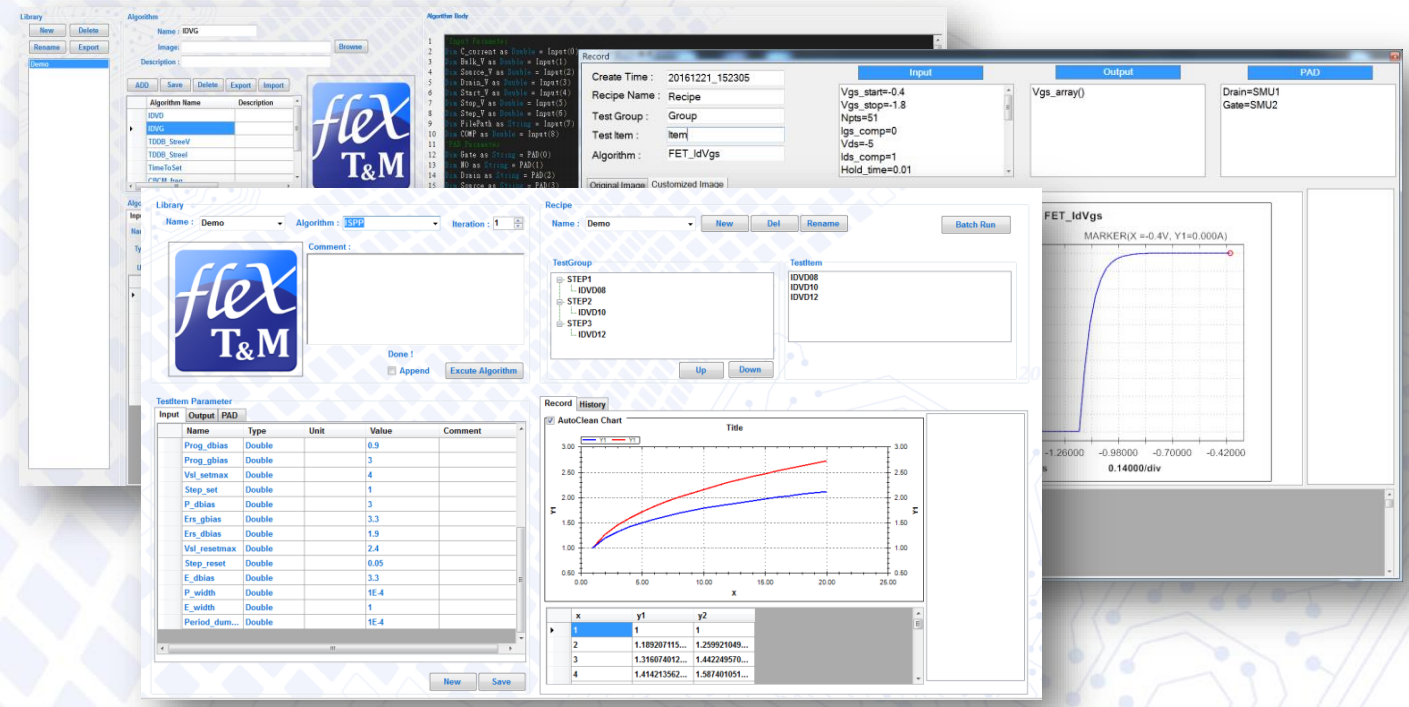
ATE(within 50MHz)

- ✓ Open/Short
- ✓ MCU
- ✓ MEMS
- ✓ DIGITAL I/O
- ✓ LOGIC IC



Microscopy

- ✓ Zoom Microscope
- ✓ Measuring Microscope
- ✓ OLED Measuring Microscope
- ✓ IR TEST SYSTEM
- ✓ BJV Test Systems
- ✓ LCD Optic
- ✓ Flatness Measurement Systems
- ✓ OCR Glue water Thickness Measuring Systems
- ✓ Electric testing machine
- ✓ Laser Repair
- ✓ 3D Laser Microscope



- Simple parameter setting.
- Batch run.
- Real time Plotting.
- Raw data format customized.
- Open source for test algorithm develop.
- Test algorithm create/modify/debug.
- Simple management test algorithms.
- Thermal control/ Backlight control



# RDL testing - Manual (Leakage Res)

## ➤ Flex-T&M Manual Mode

- For device characteristic quick check
- Inline automatic measurement process recipe setup (Option)
- Testing item include :
  - *Wafer Bumping Leakage & Res,*
  - *FPD TFT IV (IdVg/IdVd),*
  - *CV,*
  - *Kelvin testing(R4T)...etc.*
- Measurement report save as .csv file

**Testing Item Select**

- ✓ Library : Testing library
- ✓ Algorithm : Testing algorithm

**Testing Parameter Setup**

Input	Output	PAD	Name	Type	Unit	Value	Comment
			V_Force	Double	V	1.5	Force Voltage
			Npts	Double		10	Measurement Poi...
			I_comp	Double	A	0.01	DO NOT USE 0A
			Nplc	Double		16	1 - 16
			Unit	Double	A	1E-12	Scientific Unit
			HoldTime	Double	Sec	1	Holdtime
			DelayTime	Double	Sec	1	DelayTime
			SpecLimit_...	Double	A	0	Spec "min"
			SpecLimit_...	Double	A	0.2E-12	Spec "Max"
			offset_window	Double	A	0.07E-12	offset window val...
			offset_times	Double	A	0	0 = func. off, offse...
			offset_add	Double	A	-0.03E-12	offset add value
			Value_Type	Double		1	[1] Max, [2] Avera...

**Auto Recipe Setup**

- ✓ Create & Edit the auto run recipe

**Chart Display (Option)**

- ✓ Shows the testing data as IV curve chart

**Testing Results Display**

- ✓ Shows the testing value and judgement result

Leakage	Judgement
0.07	PASS

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# RDL testing - Auto (Leakage Res)

## ➤ Flex-T&M Auto Mode for RDL Testing

- For inline automatic process RDL testing run
- Testing item include : Wafer Bumping Leakage & Res
- Measurement report save as .csv file
- Prober communication

The screenshot displays the Flex-T&M Ver.1.55 software interface. At the top left, there are 'Automatic' and 'Manual' mode buttons. The 'Information' panel on the left contains the following data:

Information	
Recipe	19
Lot ID	0014
Cassette ID	UUUUUUUU
Slot ID	2
Wafer ID	AL
TestKeyGroup	3000
X	20
Y	20

Below the information panel is a 'Running' button. The 'Wafer Map' panel on the right shows an IV curve chart with the y-axis ranging from 1.00E-13 to 1.00E-04 and the x-axis from -30 to 30. The curve shows a characteristic S-shape. Below the chart is the 'Automatic Test Data' panel, which displays:

Automatic Test Data	
ResValue=0.7	(1) : 0.07
	(2) : 0.07
ResArray	(3) : 0.7
	(4) : 0.7
-0.1	
-0.7	
-0.1	
-0.7	
-0.1	

The 'Prober Log' and 'Error\_Log' panel at the bottom left shows a list of communication logs with timestamps and data points. The Pomme logo is visible in the bottom left corner of the interface.

### Testing Information Display

- ✓ Testing information for current auto run process

### Chart Display (Option)

- ✓ Shows the testing data as IV curve chart

### Communication Log Display

### Testing Results Display

- ✓ Shows the testing value



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